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		Number			Kind Cod	I I			of Cited Document MM-DD-YYY			
OW)	5,903,021					Lee et al.	· · · · · ·		05/11/99		_
UNI		6,051,44				Lee et al.			04/18/00			
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Examiner's Initials#	Cite No.	Foreign Patent Document					Name of Patentee or Applicant of Cited Document (not necessary)			Date of		
		Office/			Kind					Publication of	Cited Document (Y/N)	
		Country Number		Code		MM-DD-YYYY						
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				OTHER	ART 1	NON	N PATENT LITERA	TURE DOCUMEN	TS			
Examiner's	Cite	Include	name o				AL LETTERS) title o), title of the item	Transla	
Initials#	No						osium, catalog, etc.), date, relevant page(s), volume-issue nu			-issue number(s),	(Y/	N)
		publisher, city and/or country where published. <u>French Search Report from French Patent Application 01 01880, filed February 12, 2001.</u>								1		
			-		-				-			
		F	Patent A	bstracts of	Janan, v	. a	998, no. 09, July 31,	1998 & IP 10 0981	75 A (Tost	niha Corp.)	_	-
I W		•				··· •	,,,,		(. 001			
OU)		Furum	iya M. 6	et al., "Hig	h Sensiti	vity	and No-Cross-Talk I	Pixel Technology Fo	r Embedde	ed CMOS Image	 	
COUI.	/	Sensor" Ir	nternatio	onal Electro	on Device	es M	feeting 2000. IEDM.	Technical Digest, S	an Francis	co, CA, Dec. 10-13,		
- 4				2000, 1	New/Ýorl	k, N	Y: IEEE, US, Decer	nber 10, 2000, pages	s 701-704		<u> </u>	
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